	Application No.	Applicant(s)
Notice of Allowability	10/081,046	GILL, HARDAYAL SINGH
	Examiner	Art Unit
	Christopher R. Magee	2653
- The MAILING DATE of this communication apperature All claims being allowable, PROSECUTION ON THE MERITS IS herewith (or previously mailed), a Notice of Allowance (PTOL-85) NOTICE OF ALLOWABILITY IS NOT A GRANT OF PATENT R of the Office or upon petition by the applicant. See 37 CFR 1.313	(OR REMAINS) CLOSED in the or other appropriate communi IGHTS. This application is sub-	nis application. If not included cation will be mailed in due course. THIS
1. 🔀 This communication is responsive to the Appeal Brief filed	on 2/22/2005.	
2. The allowed claim(s) is/are <u>1-23</u> .		
3. The drawings filed on 2/20/2002 are accepted by the Exan	niner.	
<ul> <li>4. ☐ Acknowledgment is made of a claim for foreign priority ur</li> <li>a) ☐ All b) ☐ Some* c) ☐ None of the:</li> <li>1. ☐ Certified copies of the priority documents have</li> <li>2. ☐ Certified copies of the priority documents have</li> <li>3. ☐ Copies of the certified copies of the priority do</li> <li>International Bureau (PCT Rule 17.2(a)).</li> <li>* Certified copies not received:</li> </ul>	e been received. e been received in Application	No
Applicant has THREE MONTHS FROM THE "MAILING DATE" noted below. Failure to timely comply will result in ABANDONN THIS THREE-MONTH PERIOD IS NOT EXTENDABLE.	of this communication to file a IENT of this application.	reply complying with the requirements
5. A SUBSTITUTE OATH OR DECLARATION must be subm INFORMAL PATENT APPLICATION (PTO-152) which give	itted. Note the attached EXAMes reason(s) why the oath or de	IINER'S AMENDMENT or NOTICE OF eclaration is deficient.
<ol> <li>CORRECTED DRAWINGS ( as "replacement sheets") must (a)  including changes required by the Notice of Draftspers 1)  hereto or 2)  to Paper No./Mail Date</li> <li>(b)  including changes required by the attached Examiner's Paper No./Mail Date</li> <li>Identifying indicia such as the application number (see 37 CFR 1 each sheet. Replacement sheet(s) should be labeled as such in to 7.  DEPOSIT OF and/or INFORMATION about the depoattached Examiner's comment regarding REQUIREMENT</li> </ol>	son's Patent Drawing Review ( . s Amendment / Comment or in .84(c)) should be written on the he header according to 37 CFR sit of BIOLOGICAL MATER	the Office action of drawings in the front (not the back) of 1.121(d). RIAL must be submitted. Note the
Attachment(s)  1. ☑ Notice of References Cited (PTO-892)  2. ☐ Notice of Draftperson's Patent Drawing Review (PTO-948)  3. ☐ Information Disclosure Statements (PTO-1449 or PTO/SB/0 Paper No./Mail Date  4. ☐ Examiner's Comment Regarding Requirement for Deposit of Biological Material	6. ☐ Interview Sum Paper No./Ma 98), 7. ☐ Examiner's An	rmal Patent Application (PTO-152) Imary (PTO-413), ail Date nendment/Comment atement of Reasons for Allowance
,		

Application/Control Number: 10/081,046

Art Unit: 2653

## **DETAILED ACTION**

## Response to Appeal Brief

- 1. Applicant's arguments on pages 7-12 of Appeal Brief, filed 02/22/2005, with respect to Hasegawa et al. (hereinafter Hasegawa) (US 6,496,338) and/or Gill (US 6,052,263), have been fully considered and are persuasive. The finality of the last Office Action, dated 03/24/2004, has been withdrawn.
- 2. All relevant objections and rejections are withdrawn as being satisfied

## Reasons for Allowance

3. Claims 1-23 are allowed.

The following is an examiner's statement of reasons for allowance:

This application is for a MAGNETORESISTANCE SENSOR HAVING AN ANTIFERROMAGNETIC PINNING LAYER WITH BOTH SURFACES PINNING FERROMAGNETIC BIAS LAYERS.

• Claims 1, 7 and 18 specify a magnetoresistance sensor structure, which requires:

"an upper ferromagnetic layer overlying and contacting at least a portion of the upper antiferromagnetic layer on a contact face lying parallel to the sensor surface plane, so that the upper antiferromagnetic layer lies between the upper ferromagnetic layer and the free layer."

Hasegawa '338 teaches the ferromagnetic layer [47] on the antiferromagnetic layers [46] are provided so that the ends thereof cover the sides of the free ferromagnetic layer [44] to about half of the thickness thereof (col. 11, lines 12-15 and Fig. 3). The ferromagnetic layer [47] and the antiferromagnetic layer [46] fail to cover the free ferromagnetic layer on a contact surface

that is parallel to the sensor surface plane but rather on a plane more nearly perpendicular to the sensor surface plane.

Therefore, these features, in combination with other features of claims 1, 7 and 18 are not anticipated by, nor made obvious over, the closest prior art of record of Hasegawa '338.

• Claims 6 and 17 specify a magnetoresistance sensor structure, which requires:

"an upper antiferromagnetic layer overlying substantially all the free layer" and "a cap layer overlying the upper ferromagnetic layer."

Hasegawa '338 shows an upper antiferromagnetic layer [46] overlying a portion of the free layer [44] but does not teach or suggest an upper antiferromagnetic layer overlying substantially all the free layer and a cap layer overlying the upper ferromagnetic layer as claimed in the present invention.

• Claim 13 specifies a magnetoresistance sensor structure, which requires:

"an upper ferromagnetic layer overlying a first portion of the free layer that is less than all of the free layer and contacting the upper antiferromagnetic layer on a contact face lying parallel to the sensor surface plane, so that the upper antiferromagnetic layer lies between the upper ferromagnetic layer and the free layer;" and "a cap layer overlying the upper ferromagnetic layer."

Hasegawa '338 teaches the ferromagnetic layer [47] on the antiferromagnetic layers [46] are provided so that the ends thereof cover the sides of the free ferromagnetic layer [44] to about half of the thickness thereof (col. 11, lines 12-15 and Fig. 3). The ferromagnetic layer [47] and the antiferromagnetic layer [46] fail to cover the free ferromagnetic layer on a contact surface that is parallel to the sensor surface plane but rather on a plane more nearly

perpendicular to the sensor surface plane. Further, Hasegawa '338 does not teach or suggest a

cap layer overlying the upper ferromagnetic layer as claimed in the present invention.

Therefore, these features, in combination with other features of claim 13 are not

anticipated by, nor made obvious over, the closest prior art of record of Hasegawa '338.

Claims 21-23 specify a magnetoresistance sensor structure, which requires:

"an upper ferromagnetic layer overlying and contacting at least a portion of the upper antiferromagnetic layer on a contact face lying parallel to the sensor surface plane, so that the upper antiferromagnetic layer lies between the upper ferromagnetic layer and the free layer in a

plane parallel to the sensor surface plane."

Hasegawa '338 teaches the ferromagnetic layer [47] on the antiferromagnetic layers [46]

are provided so that the ends thereof cover the sides of the free ferromagnetic layer [44] to about

half of the thickness thereof (col. 11, lines 12-15 and Fig. 3). The ferromagnetic layer [47] and

the antiferromagnetic layer [46] fail to cover the free ferromagnetic layer on a contact surface

that is parallel to the sensor surface plane but rather on a plane more nearly perpendicular to the

sensor surface plane.

Therefore, these features, in combination with other features of claims 21-23, are not

anticipated by, nor made obvious over, the closest prior art of record of Hasegawa '338.

Any comments considered necessary by applicant must be submitted no later than the 4.

payment of the issue fee and, to avoid processing delays, should preferably accompany the issue

fee. Such submissions should be clearly labeled "Comments on Statement of Reasons for

Allowance."

Application/Control Number: 10/081,046

Art Unit: 2653

Conclusion

5. Any inquiry concerning this communication or earlier communications from the

examiner should be directed to Christopher R. Magee whose telephone number is (571) 272-

7592. The examiner can normally be reached on M-F, 8: 00 am-5: 30 pm.

If attempts to reach the examiner by telephone are unsuccessful, the examiner's

supervisor, William Korzuch can be reached on (571) 272-7589. The fax phone number for the

organization where this application or proceeding is assigned is 703-872-9306.

Information regarding the status of an application may be obtained from the Patent

Application Information Retrieval (PAIR) system. Status information for published applications

may be obtained from either Private PAIR or Public PAIR. Status information for unpublished

applications is available through Private PAIR only. For more information about the PAIR

system, see http://pair-direct.uspto.gov. Should you have questions on access to the Private PAIR

system, contact the Electronic Business Center (EBC) at 866-217-9197 (toll-free).

Christopher R. Magee

Patent Examiner

Art Unit 2653

May 30, 2005

WILLIAM KORZUCH

Page 5

SUPERVISORY PATENT EXAMINER

**TECHNOLOGY CENTER 2600**